

High Speed Window Comparator

AD53042

FEATURES

-2 V to +7 V Input Voltage Range Low V_{IN} Bias Current (<100 nA) Up to 5 V/ns Input Signal Tracking Low Dispersion of \pm 100 ps 28-Lead PLCC Package

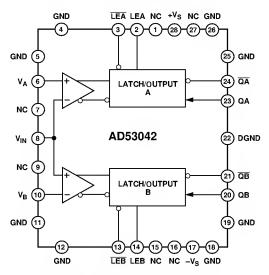
APPLICATIONS
Automatic Test Equipment
Semiconductor Test Systems
Board Test Systems

PRODUCT DESCRIPTION

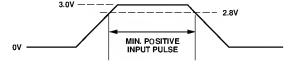
The AD 53042 is an ultrahigh speed window comparator with latch. It uses a high speed monolithic process to provide high dc accuracy without sacrificing input voltage range. On-chip connection of the common input eliminates the contributions of a second bonding pad and package pin to the input capacitance, resulting in a maximum input capacitance of 2 pF .

The AD 53042 employs a high precision differential input stage with a common mode range of 9 V. Its complementary digital outputs are fully ECL compatible. The output stage is capable of driving a 50 Ω line terminated to –2 V. The device also provides a latch function, allowing operation in track-hold mode and can also be used to generate hysteresis.

FUNCTIONAL BLOCK DIAGRAM



NOTE: NOT THE ACTUAL PHYSICAL LAYOUT OF DEVICE. NC = NO CONNECTION INSIDE PACKAGE.



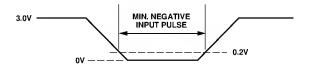


Figure 1. Typical Application Circuit

AD53042- SPECIFICATIONS (All specifications apply with $T_c = 40^{\circ}$ C to 100° C and $+V_s = +7.75$ V to +11.5 V; $-V_s = -3.95$ V to -7.7 V unless otherwise noted.)

Parameter	Min	Тур	Max	Units	Test Conditions
POWER SUPPLIES I -Positive Supply Currents I -N egative Supply Current P -Power Dissipation	-85		65 1.19	mA mA W	No Load No Load No Load, $+V_S = +10 \text{ V}$, $-V_S = -5.2 \text{ V}$
DC INPUT CHARACTERISTICS Offset Voltage (V _{OS}) V _{IN} Bias Current V _A , V _B Bias Current Capacitance V _{IN} , V _A , V _B Voltage Range (V _{CM}) Differential Voltage (V _{DIFF}) N onlinearity V _A /V _B Interaction	-10 -0.5 -20 -V _s + 2.7	<0.1>	10 0.5 20 2 +V _S - 2.5 9 5 0.1	mV μA μA pF V V mV	$CMV = 0V$ $V_{IN} = 0V$ $V_{IN} = 0V$ See Note 1
BIAS CURRENT Change vs. Comparator State Nonlinearity Tempco	-1 -2	±0.1	1 2	μΑ μΑ μΑ/°C	
LATCH ENABLE INPUTS Common-M ode Range Differential Voltage Logic "1" Current (L _{IH}) Logic "0" Current (L _{IL})	-2 0.4 -10		1 3 200	V V μΑ μΑ	
DIGITAL OUTPUTS Logic "1" Voltage (V _{OH}) Logic "0" Voltage (V _{OL})	-0.98		-1.5	V	Q or $\overline{\mathbb{Q}}$, 50 Ω to -2 V Q or $\overline{\mathbb{Q}}$, 50 Ω to -2 V
SWITCHING PERFORMANCE Propagation Delay Input to Output Part-to-Part Skew Change vs. Temperature		±1	2	ns ns ps/°C	$V_{IN} = 2 \text{ V p-p, } t_{PDR}, t_{PDF}, \text{ Figure 1, N ote 2}$
DISPERSION 5 V p-p Input (All Edges) 5 V p-p Input (All Edges) V Slew = 1 V/ns (All Edges) V Slew = 1 V/ns (All Edges) M inimum Pulsewidth Edge Interaction D uty Ratio C omparator Interaction		±100 ±175 ±50 ±50 <1 <200 <100		ps ps ps ps ps ns ps ps	10%, 90% 0.5 V/ns, 3 V/ns 10%, 90% 5 V/ns 10%, 90% 3 V, 5 V 20%, 80% 1 V See N ote 3 See N ote 4 See N ote 5

NOTES

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¹D efined as change in V_{OS} from -V_S + 2.95 V to +V_S - 2.75 V (throughout the range) after V_A and V_B are corrected for gain and offset using 0 V and 5 V.
²Propagation delay is measured from the input threshold crossing at the 50% point of a 0 V to 5 V input to the output Q and Q crossing.
³The minimum input pulsewidth that will maintain a 600 mV ECL swing on the output. The input is a 0 V to 3 V signal with a 3 V/ns rise and fall times. The input pulsewidth is measured between the 2.8 V point of a positive input pulse and the 0.2 V of a negative input pulse. See Figure 2.

Maximum Change in propagation delay as the input pulse is reduced from 50 ns to a 2 ns pulsewidth. 0 V to 3 V swing with 3 V/ns rise/fall time and 25% duty cycle. 5M aximum Change in propagation delay as the input pulse is reduced from 99% to a 1% duty cycle. 0 V to 3 V swing with 3 V/ns rise/fall time and 50 ns to 4.95 µs pulsewidth, period = $5 \mu s$.

Specifications subject to change without notice.

ABSOLUTE MAXIMUM RATINGS*

Power Supply Voltage
+V _s to GND+12 V
-V _S to GND8 V
+V _s to -V _s +17 V
Inputs
V_{1N} , V , V + V_{S} - 13.5 V , - V_{S} + 13.7 V
LEA, $\overline{\text{LEA}}$, LEB, $\overline{\text{LEB}}$ + V_S - 14 V , - V_S + 10 V
Currents
I (+V _s) 95 mA
I (-V _S)75 mA
QA, \overline{QA} , QB, \overline{QB} 40 mA to +2 mA
E nvironmental
Operating T emperature (Ambient) 0°C to +70°C
Storage T emperature65°C to +125°C
Lead Temperature (Soldering, 20 sec)+300°C

^{*}Stresses above those listed under Absolute M aximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Absolute maximum limits apply individually, not in combination. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

 $T\ he\ device\ must\ suffer\ no\ reliability\ degradation\ if\ any\ supply\ pin\ is\ either\ shorted\ to\ ground\ or\ left\ floating\ for\ an\ indefinite\ periods\ of\ time\ during\ normal\ operation.$

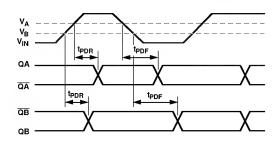
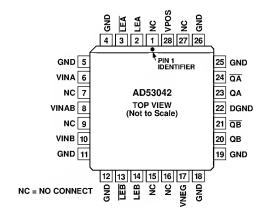


Figure 2. Timing Diagram

ORDERING GUIDE

Model	Package Description	Shipment Method, Quantity Per Shipping Container	Package Option
AD 53042K RP	28-L ead PLCC	Tube, 36 Pieces	P-28A

PIN CONFIGURATION



CAUTION_

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD 53042 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

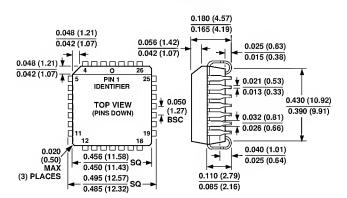


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OUTLINE DIMENSIONS

Dimensions shown in inches and (mm).

28-Lead Plastic Leaded Chip Carrier (P-28A)



-4- REV. 0